EPC2106 – Enhancement-Mode GaN Power Transistor Half-Bridge

V_{DS} , 100 V
$R_{DS(on)}$, 70 mΩ
I_D , 1.7 A

EFFICIENT POWER CONVERSION

RoHS Halogen-Free

Revised January 27, 2021

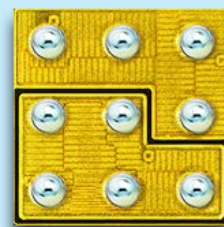
Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR}. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Questions: Ask a GaN Expert

Maximum Ratings				
DEVICE		PARAMETER	VALUE	UNIT
Q1 & Q2	V_{DS}	Drain-to-Source Voltage (Continuous)	100	V
		Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	120	
	I_D	Continuous (T_A = 25°C, $R_{\theta JA}$ = 320°C/W)	1.7	A
		Pulsed (25°C, T_{PULSE} = 300 µs)	18	
	V_{GS}	Gate-to-Source Voltage	6	V
		Gate-to-Source Voltage	–4	
	T_J	Operating Temperature	–40 to 150	°C
	T_{STG}	Storage Temperature	–40 to 150	

Thermal Characteristics			
	PARAMETER	TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	3	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	30	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	81	

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board.
See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details



Die Size: 1.35 x 1.35 mm

EPC2106 eGaN® ICs are supplied only in passivated die form with solder bumps.

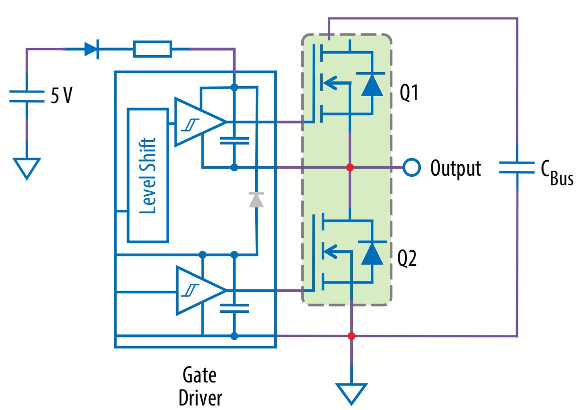
Applications

- High frequency DC-DC conversion
- Class-D audio

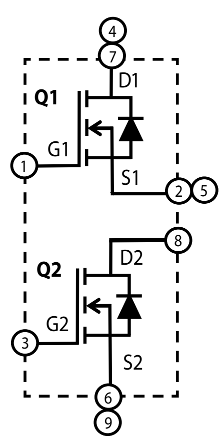
Benefits

- Ultra high efficiency
- Ultra low $R_{DS(on)}$
- Ultra low Q_G
- Ultra small footprint

Typical Application Circuit



EPC2106 – Detailed Schematic



Scan QR code or click link below for more information including reliability reports, device models, demo boards!

https://l.ead.me/EPC2106

Static Characteristics (T_J = 25˚C unless otherwise stated)							
DEVICE	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Q1 & Q2	BV_{DSS}	Drain-to-Source Voltage	V_{GS} = 0 V, I_D = 0.3 mA	100			V
	I_{DSS}	Drain-Source Leakage	V_{DS} = 80 V, V_{GS} = 0 V		0.001	0.25	mA
	I_{GSS}	Gate-to-Source Forward Leakage	V_{GS} = 5 V		0.01	1	mA
		Gate-to-Source Reverse Leakage	V_{GS} = -4 V		0.001	0.25	mA
	$V_{GS(TH)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 0.6 mA	0.8	1.4	2.5	V
	$R_{DS(on)}$	Drain-Source On Resistance	V_{GS} = 5 V, I_D = 2 A		55	70	mΩ
	V_{SD}	Source-Drain Forward Voltage	I_S = 0.35 A, V_{GS} = 0 V		2.1		V

Dynamic Characteristics (T_J = 25˚C unless otherwise stated)							
DEVICE	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Q1	C_{ISS}	Input Capacitance	V_{DS} = 50 V, V_{GS} = 0 V		79	95	pF
	C_{RSS}	Reverse Transfer Capacitance			0.5		
	C_{OSS}	Output Capacitance			52	78	
	$C_{OSS(ER)}$	Effective Output Capacitance, Enegy Related (Note 2)	V_{DS} = 0 to 50 V, V_{GS} = 0 V		63		
	$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			79		
	R_G	Gate Resistance			1.3		Ω
	Q_G	Total Gate Charge	V_{DS} = 50 V, V_{GS} = 5 V, I_D = 2 A		730	900	pC
	Q_{GS}	Gate to Source Charge	V_{DS} = 50 V, I_D = 2 A		240		
	Q_{GD}	Gate to Drain Charge			140		
	$Q_{G(TH)}$	Gate Charge at Threshold			165		
	Q_{OSS}	Output Charge	V_{DS} = 50 V, V_{GS} = 0 V		3960	5940	
	Q_{RR}	Source-Drain Recovery Charge			0		
Q2	C_{ISS}	Input Capacitance	V_{DS} = 50 V, V_{GS} = 0 V		79	95	pF
	C_{RSS}	Reverse Transfer Capacitance			0.5		
	C_{OSS}	Output Capacitance			61	92	
	$C_{OSS(ER)}$	Effective Output Capacitance, Enegy Related (Note 2)	V_{DS} = 0 to 50 V, V_{GS} = 0 V		74		
	$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			94		
	R_G	Gate Resistance			1.8		Ω
	Q_G	Total Gate Charge	V_{DS} = 50 V, V_{GS} = 5 V, I_D = 2 A		730	900	pC
	Q_{GS}	Gate to Source Charge	V_{DS} = 50 V, I_D = 2 A		240		
	Q_{GD}	Gate to Drain Charge			140		
	$Q_{G(TH)}$	Gate Charge at Threshold			165		
	Q_{OSS}	Output Charge	V_{DS} = 50 V, V_{GS} = 0 V		4680	7020	
	Q_{RR}	Source-Drain Recovery Charge			0		

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.
Note 3: $C_{OSS(ER)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 1 (Q1 & Q2): Typical Output Characteristics at 25°C

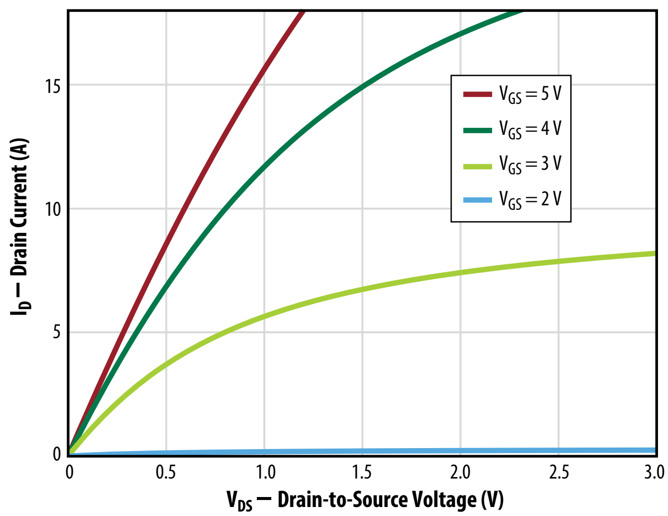


Figure 2 (Q1 & Q2): Typical Transfer Characteristics

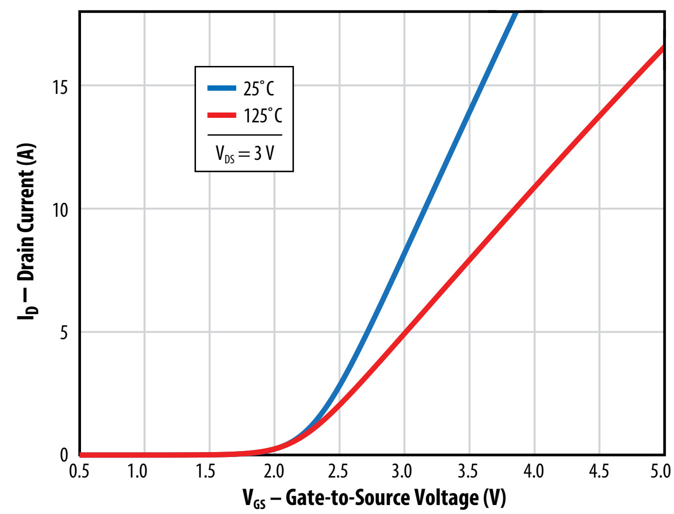


Figure 3 (Q1 & Q2): Typical $R_{DS(on)}$ vs. V_{GS} for Various Drain Currents

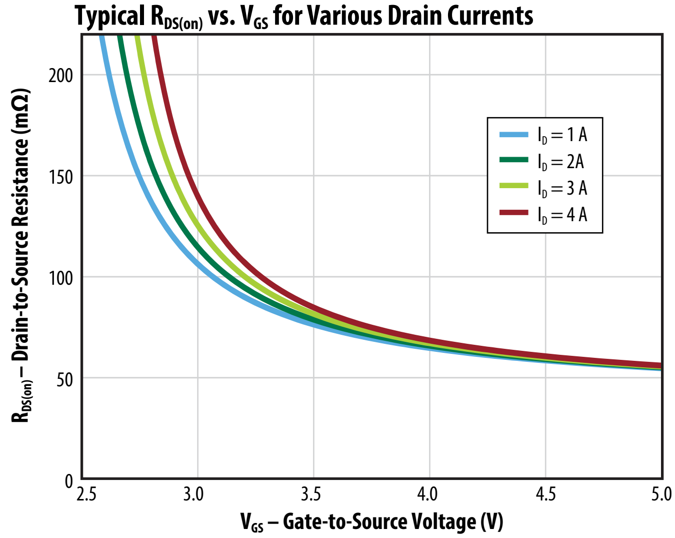


Figure 4 (Q1 & Q2): Typical $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

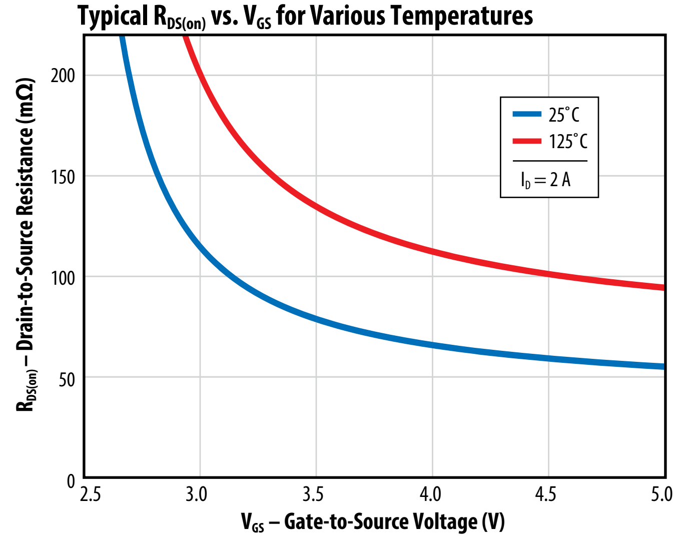


Figure 5a (Q1): Typical Capacitance (Linear Scale)

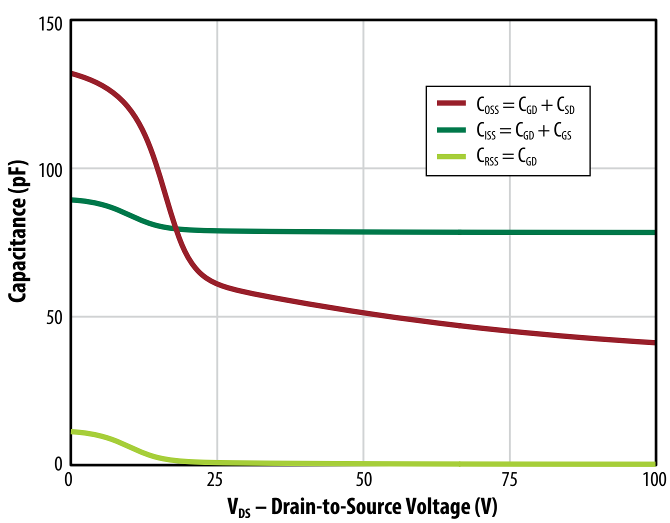


Figure 5b (Q1): Typical Capacitance (Log Scale)

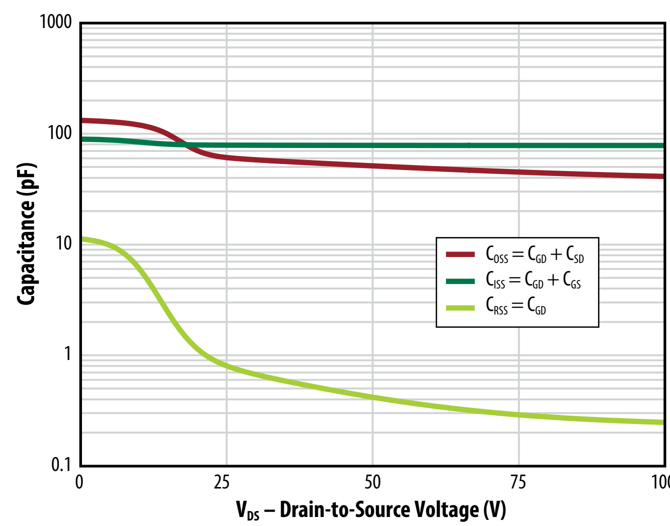


Figure 5c (Q2): Typical Capacitance (Linear Scale)

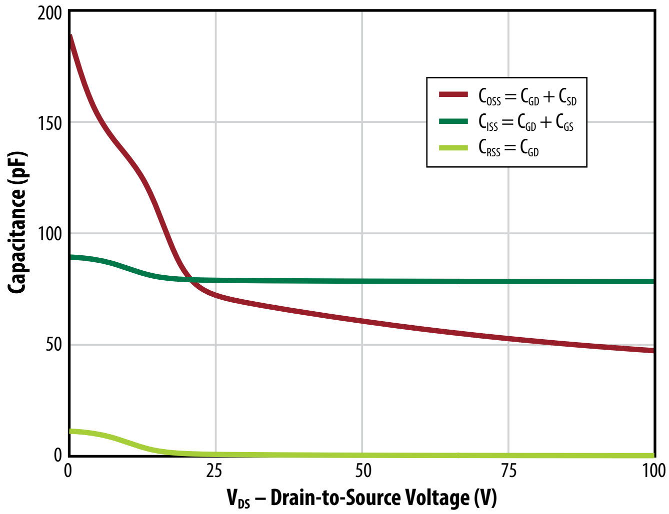


Figure 5d (Q2): Typical Capacitance (Log Scale)

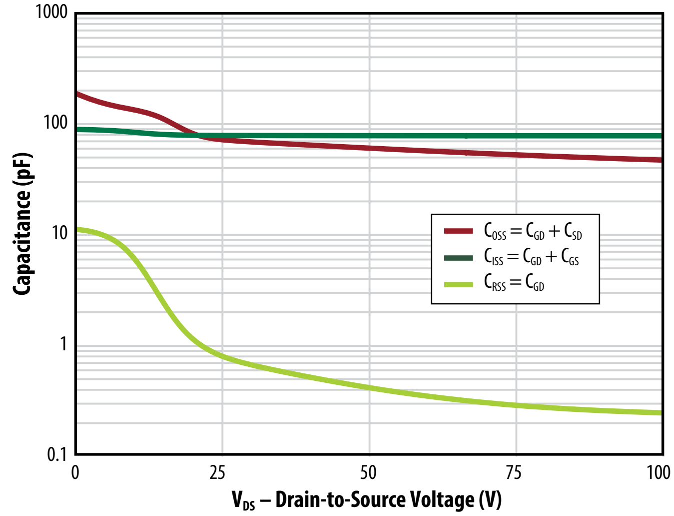


Figure 6a (Q1): Typical Output Charge and C_{OSS} Stored Energy

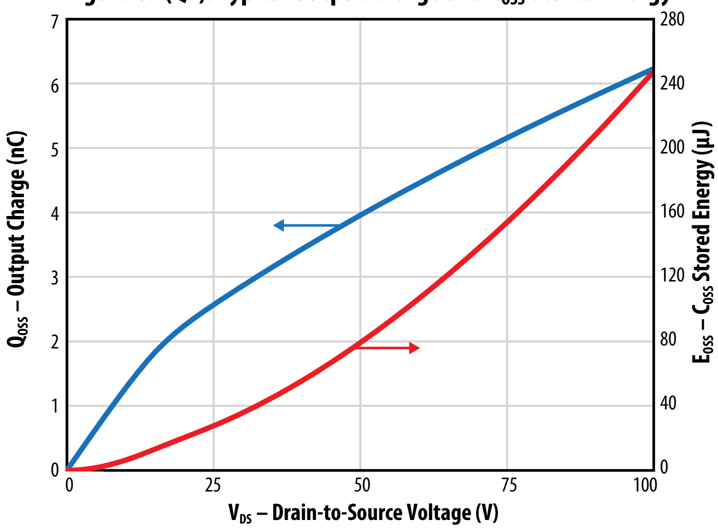


Figure 6b (Q2): Typical Output Charge and C_{OSS} Stored Energy

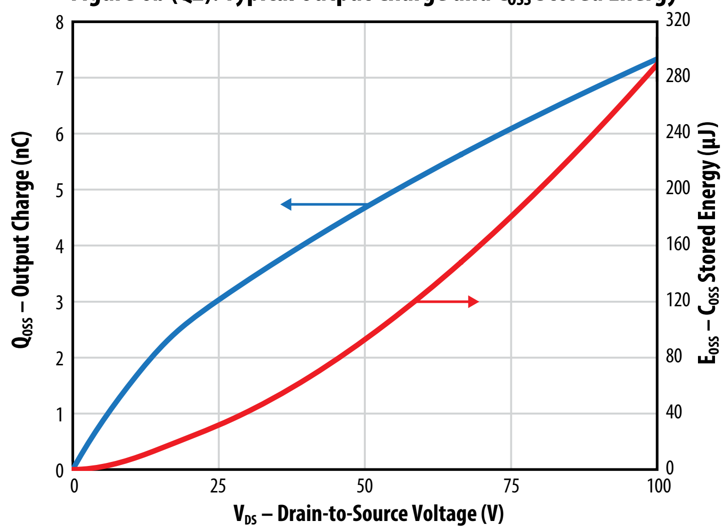


Figure 7 (Q1 & Q2): Typical Gate Charge

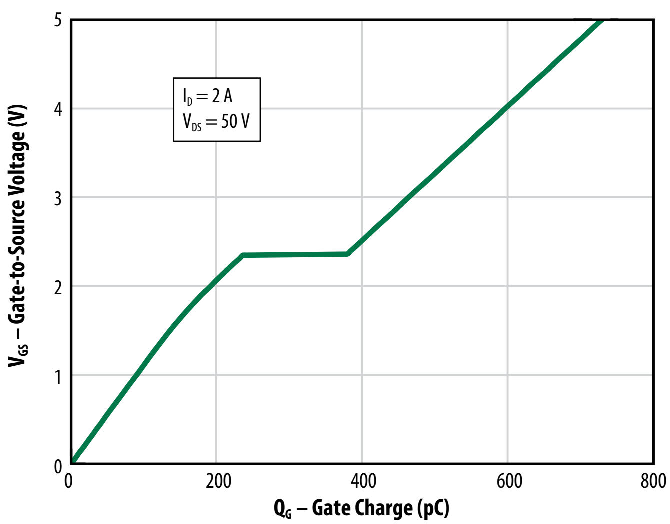
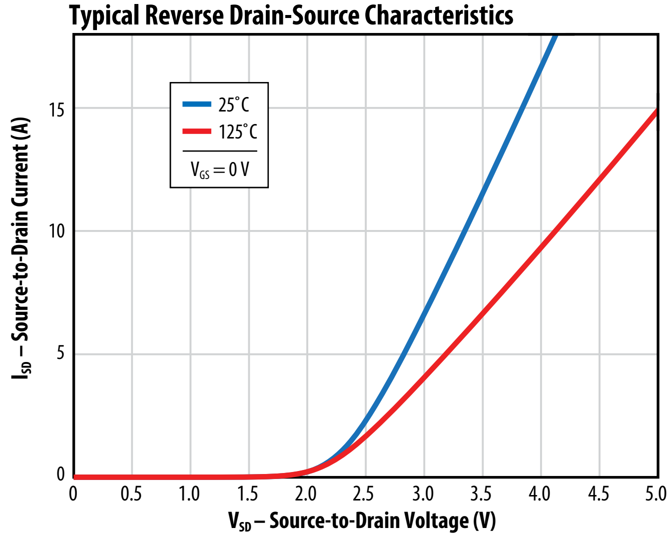


Figure 8 (Q1 & Q2): Typical Reverse Drain-Source Characteristics



Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

Figure 9 (Q1 & Q2):
Typical Normalized On-State Resistance vs. Temperature

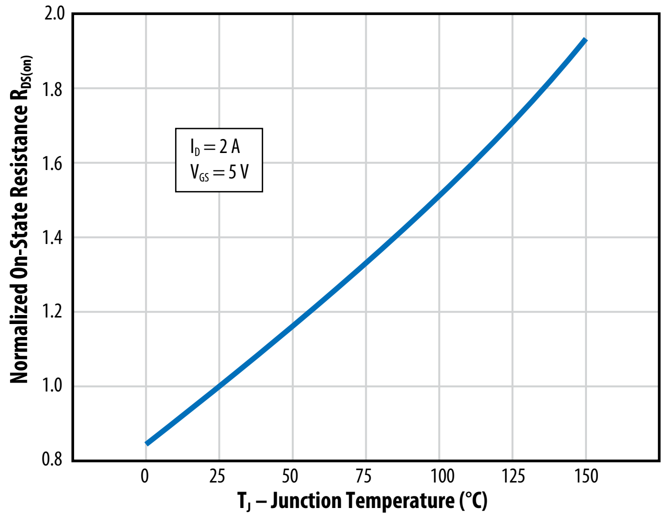


Figure 10 (Q1 & Q2):
Typical Normalized Threshold Voltage vs. Temperature

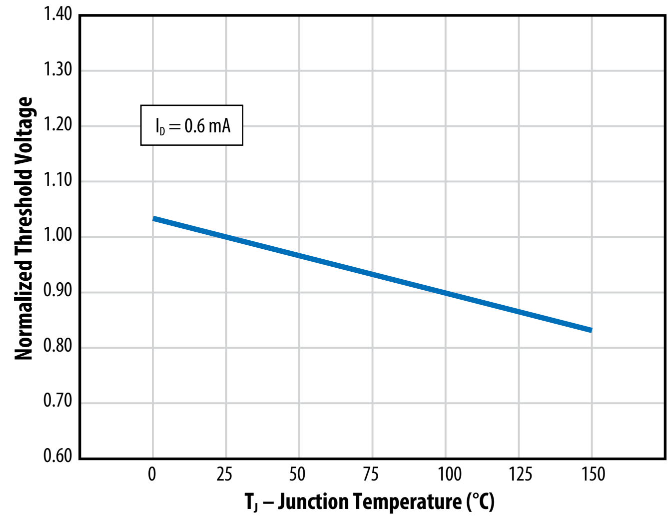
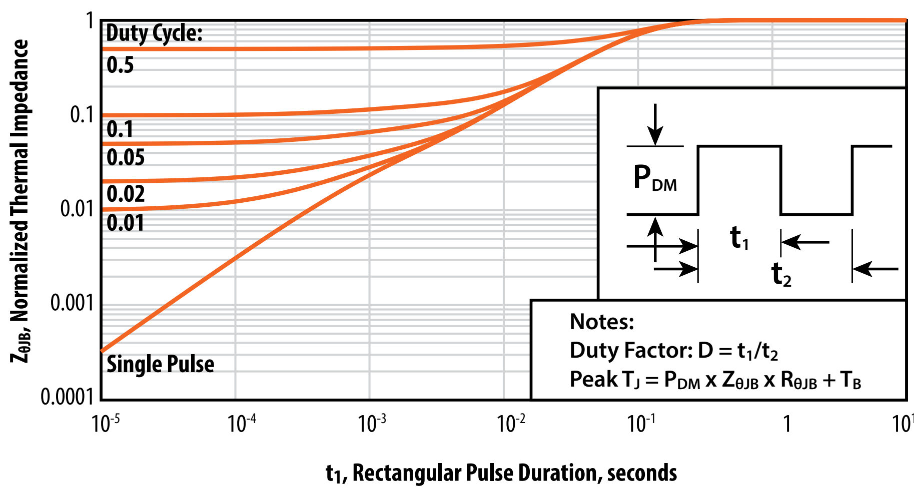


Figure 12 (Q1 & Q2): Typical Transient Thermal Response Curves

(Q1 & Q2) Junction-to-Board



(Q1 & Q2) Junction-to-Case

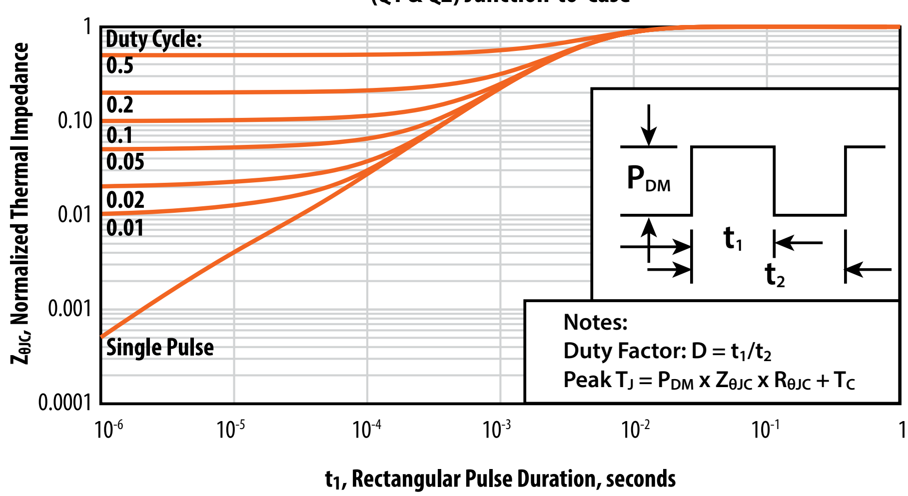
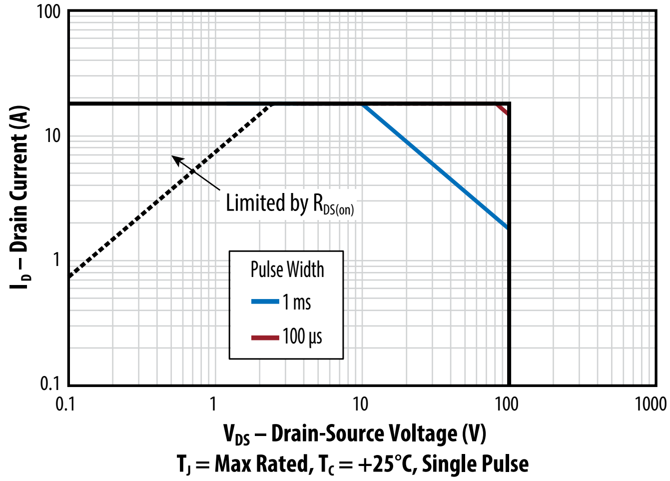
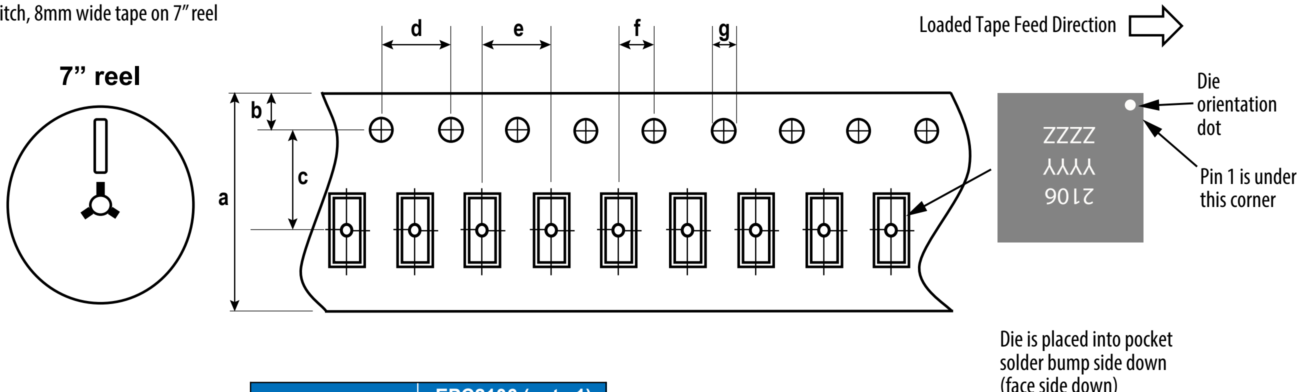


Figure 12 (Q1 & Q2): Safe Operating Area



TAPE AND REEL CONFIGURATION

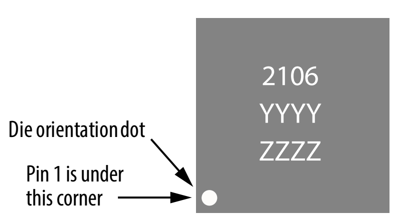
4mm pitch, 8mm wide tape on 7" reel



	EPC2106 (note 1)		
Dimension (mm)	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (see note)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (see note)	2.00	1.95	2.05
g	1.5	1.5	1.6

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.
Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

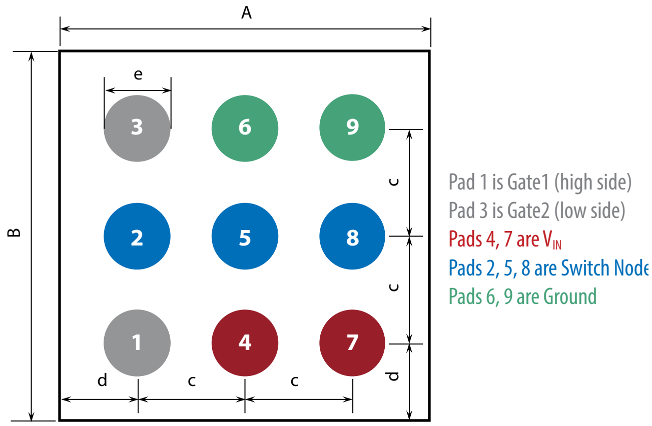
DIE MARKINGS



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2106	2106	YYYY	ZZZZ

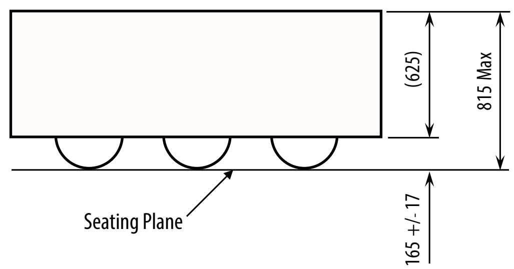
DIE OUTLINE

Solder Bump View



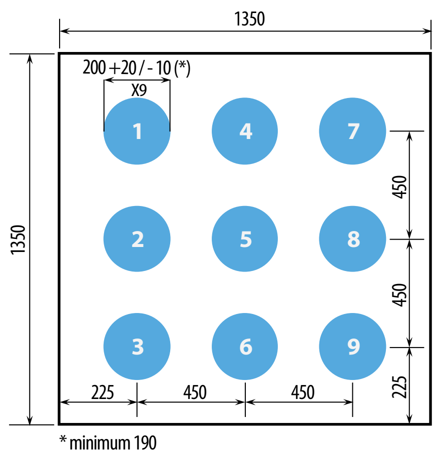
DIM	Micrometers		
	MIN	Nominal	MAX
A	1320	1350	1380
B	1320	1350	1380
c	450	450	450
d	210	225	240
e	187	208	229

Side View



RECOMMENDED LAND PATTERN

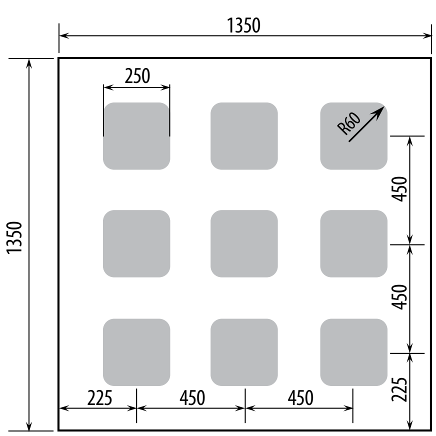
(measurements in µm)



The land pattern is solder mask defined.

RECOMMENDED STENCIL DRAWING

(measurements in µm)



Recommended stencil should be 4 mil (100 µm) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx